Hybrid 8j395 Traveler

July 14, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J395 has die: 242-069 242-071 242-078 242-072 172-121 172-122 172-123 172-124

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j395 classification info. Created 11:21:59 07/12/00

Hybrid 8j395 quality: fair
Chip classification: fair fair good fair good good good good
Bad channels (chip-channel): 0-47 1-35 3-14
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-0-102 1-1-102 1-10-102
   1-10-103 1-12-102 1-12-103 1-21-101 1-21-102 1-21-103 1-22-102 1-5-102
   1-5-103 1-6-102 1-8-102 1-8-103 1-9-102
Channels at pedestal needed for DCMS: 32.6 29.7 31.7 31.6 36.6 35.6 32.7 32.6
```

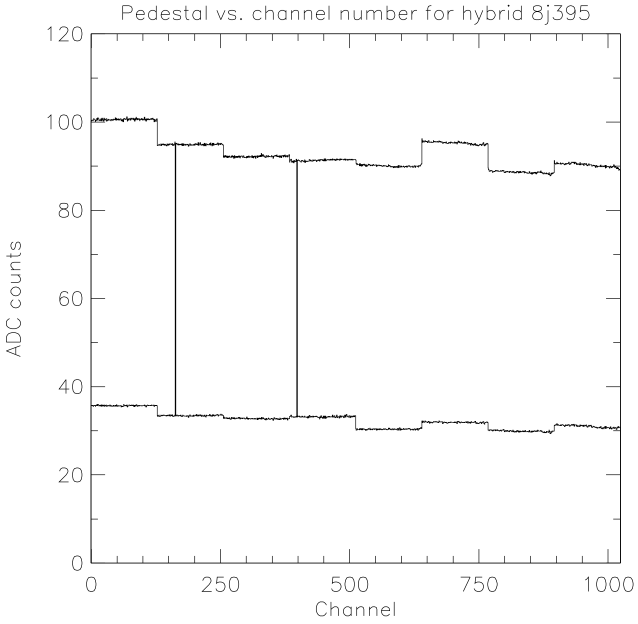
4 Comments

HV tested.

5 Pedestal

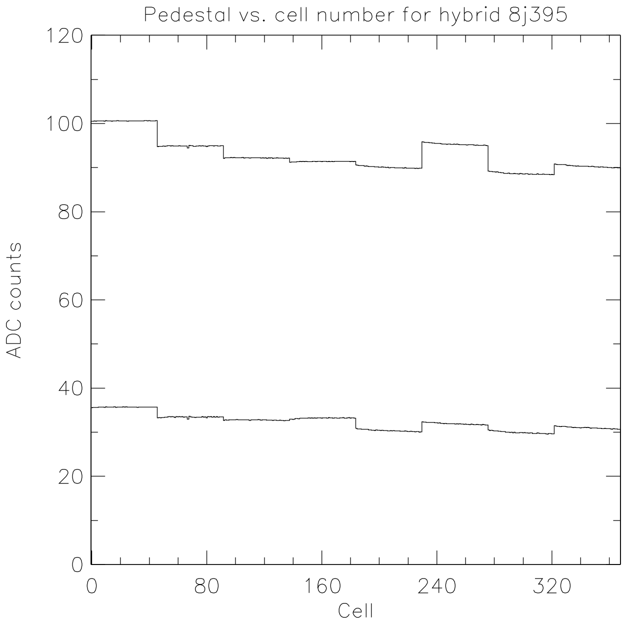
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

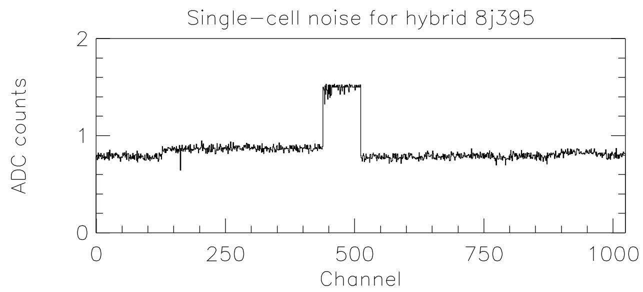
Pedestal vs. Pipeline Cell ID

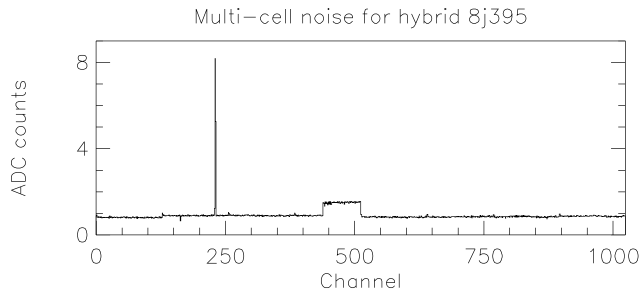


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

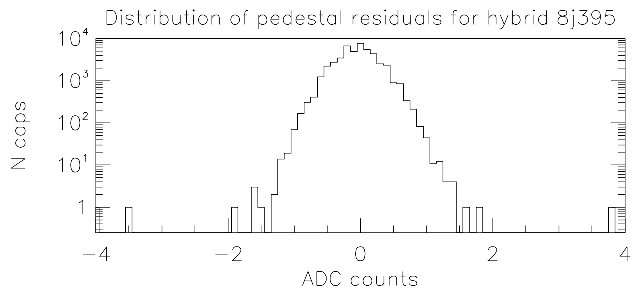
RMS Noise

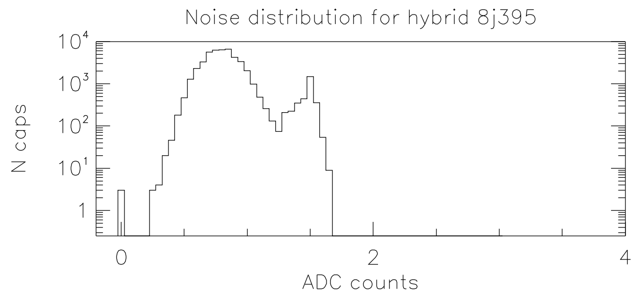




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in